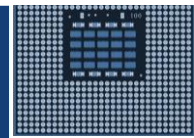




Open-Silicon.com

490 N. McCarthy Blvd, #220
Milpitas, CA 95035
408 240-5700

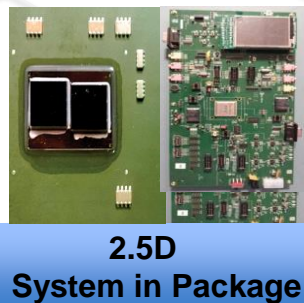
HQ



Multi-Die ASIC SiP (System in Package) Manufacturing

C O N F I D E N T I A L

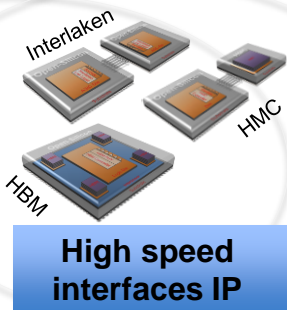
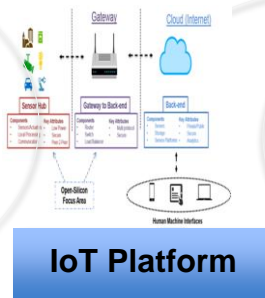
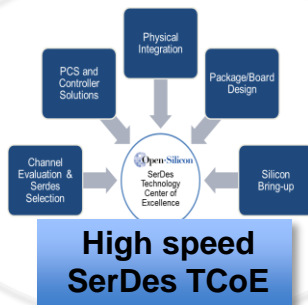
Open-Silicon



Asim Salim

VP Mfg. Operations

- 20+ experience is Semiconductor Operations Engineering (Product Engineering, Device Physics, Reliability, Supply Chain)
- Early adopter of SiPs – shipped >5M mobile graphics processors with DDR KGD memories in 1999



Multi-Die ASIC SiP (System in Package) Overview

First ASIC-vendor to bring 2.5D to prototype silicon (Avatar)
Awarded best chip-design at ARM TechCon 2013, Santa Clara

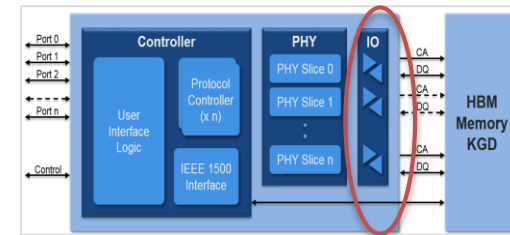
Why 2.5D has a future → Memory Wall

- Processing can see 50-75% idle times
- CPU performance is increasing 4x-8x compared to memory performance
- Power is a big issue
 - HBM uses wide-IO to reduce frequency → lower power
- IO space is limited (packaging)
 - Memory cannot become wider
- Faster data
 - USB, PCIe, SATA, all are faster now
 - Multiple interfaces vie for same DRAM
 - Larger on-chip storage is needed
 - Video/graphics is the biggest contributor

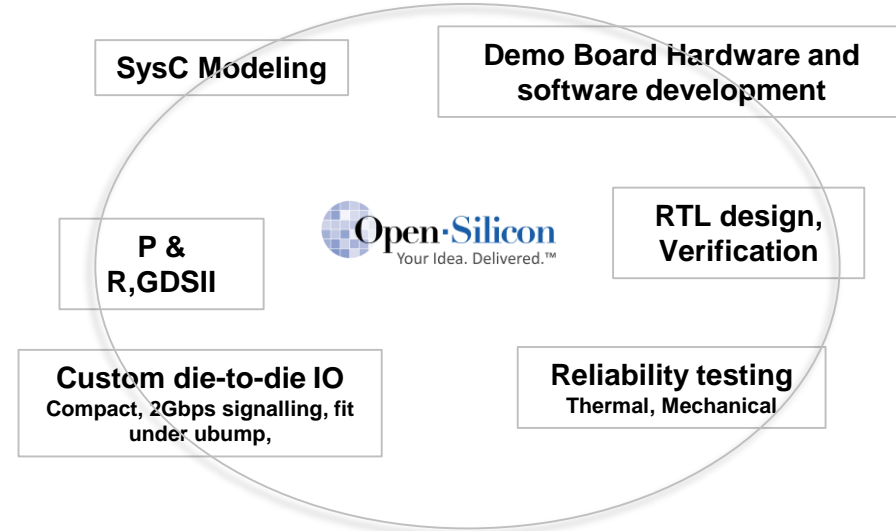
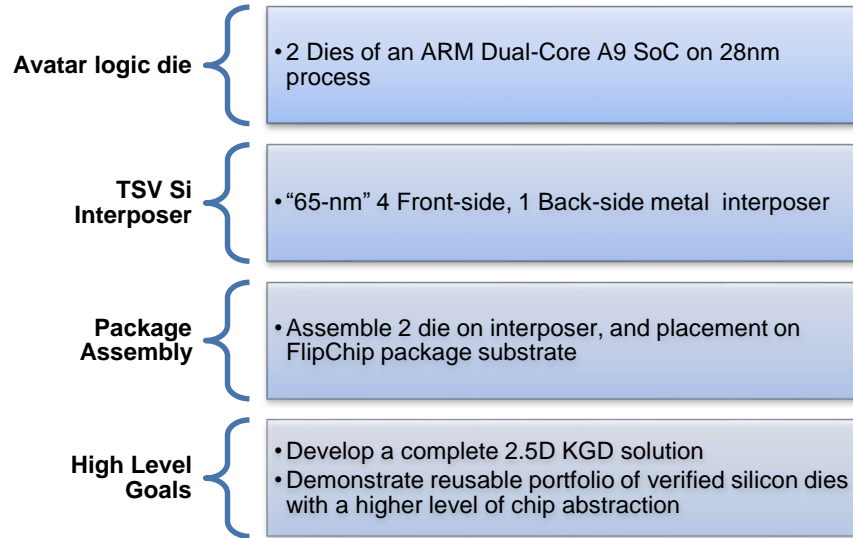


High Bandwidth Memory

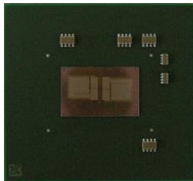
- *In-house design, Hard-IP*
- *Leveraging 2.5D die2die “channel” experience from Avatar*
- *e.g. on Interposer interconnect electricals, ESD, DfT, etc.*
- *CMOS IO driver, 1GHz/2Gbps DDR with light output loading (1 – 8mm interposer trace)*
- *Electrically compatible with JEDEC HBM DRAM spec*
- *TSMC 16FF-GL Implementation*



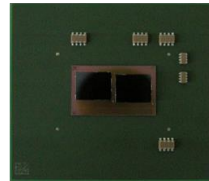
Avatar 2.5D Solution Demonstration



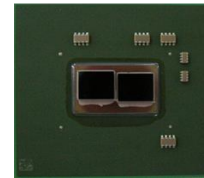
Interposer + Cap



w/AVATAR



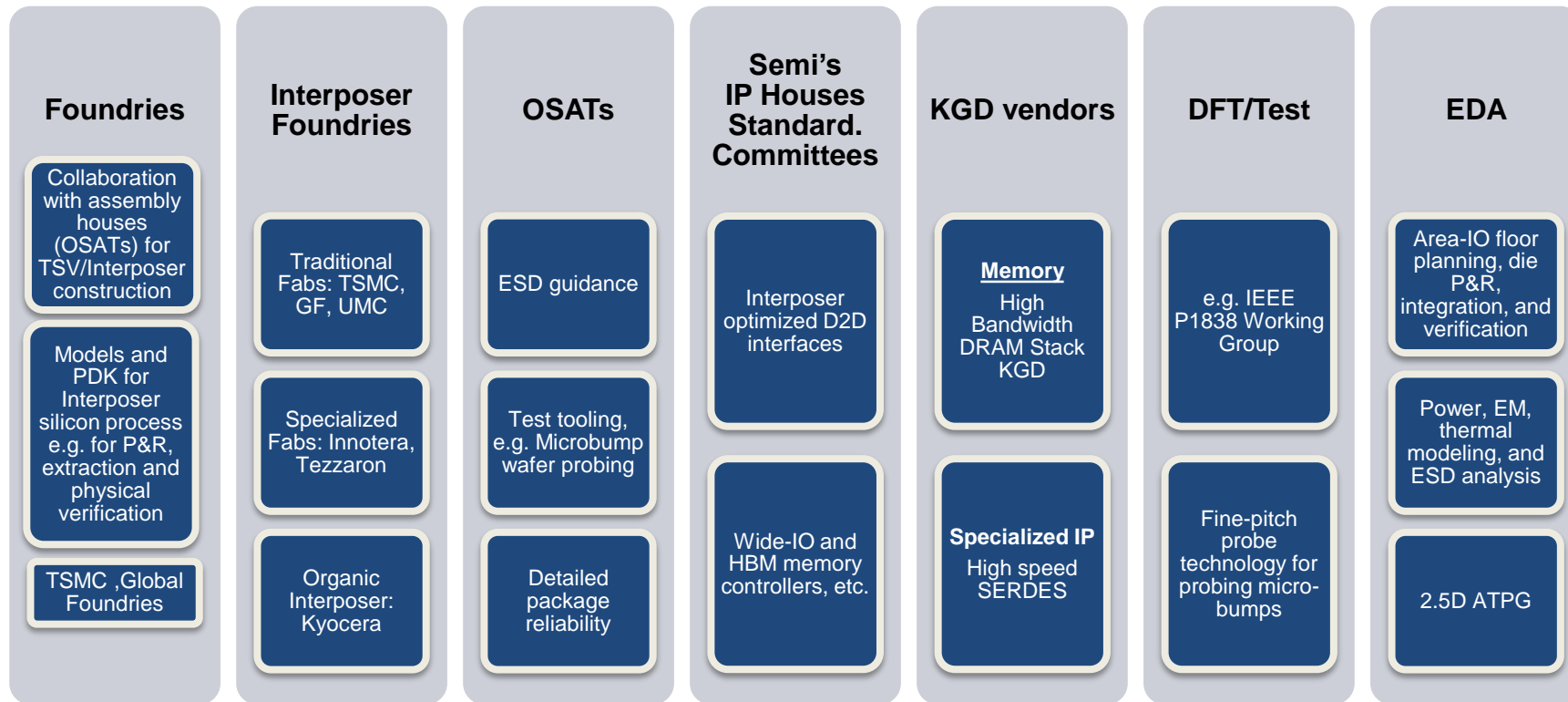
w/Underfill



Lid attach

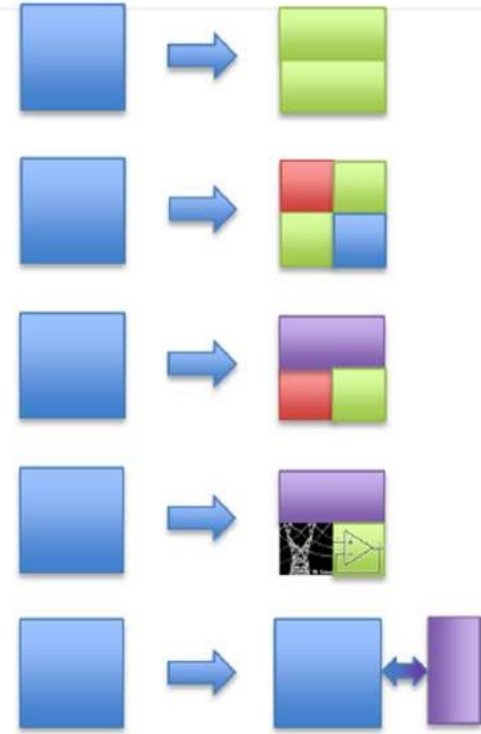


Building the Ecosystem



Additional Benefits Of 2.5D Based Design

- Yield Improvement for large SoC die
- Overall power improvement by mixing slow and fast parts
- Risk and Cost improvement due to process node mix
- Die partitioning and optimization for analog, performance, power management, etc.
- Integrating High Bandwidth Memory, flash, or other memory technologies



Challenges

Foundries

- Microbumping,
- > Interposers exceeding reticle size
- Reliability
- Cost

Interposer Foundries

- Keep Costs Low
- Optimize Number of Metal Layers
- Integrate passives

OSATs

- Low ESD environment
- Wafer level processing techniques
- Large stacked package reliability
- Costs

Semi's IP Houses Standard. Committees

- New additions and requirements (D2D IOs, ESD)
- new players

KGD vendors

- Standards across suppliers on Test/DFT, delivery metrics

DFT/Test

- Probing Microbumps
- Testing out at many different levels
- High-speed testing at probe

EDA

- Integrated tools connecting core die to interposer, package substrates

